



Sheet 1 of 2

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 118825	APPLICATION NO. 10/782,950	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANT Yoshihito OWA				
		FILING DATE February 23, 2003				
		U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
NP	1	6,587,381	07/01/2003	Kanai et al.		
	2	6,587,380	07/01/2003	Kanai et al.		
	3	6,646,916	11/11/2003	Kamei		
	4	20030072191 A1	04/17/2003	Kamei		
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	6	6,707,720	03/16/2004	Kamei et al.		
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Date: July 14, 2004

MJM ✓ M 5-22-05

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	37	10/779,683 Atty. Docket # 118739	02/18/2004	Kanai			
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


EXAMINER	<i>M. J. M.</i>	DATE CONSIDERED <i>5-20-05</i>
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 118825	APPLICATION NO. New U.S. Patent Application	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANT Yoshihito OWA				
		FILING DATE February 23, 2004				
		U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
WY	1	US 6,255,166 B1	07/03/2001	OGURA et al.		
	2	US 6,248,633 B1	06/19/2001	OGURA et al.		
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	9	JP A 11-074389 w/ abst	03/16/1999	Japan		
	10	JP B1 2978477 w/ trans	09/10/1999	Japan		
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WY	13	Hayashi, Yutaka et al. "Twin MONOS Cell with Dual Control Gates." 2000 Symposium on VLSI Technology Digest of Technical Papers, 2000 IEEE				
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EXAMINER <i>WY</i> <i>J</i> <i>M</i>					DATE CONSIDERED <i>5-22-05</i>	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						